APR 2 0 2001

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

ATTY.'S DOCKET: 98 P7501 US

In re the application of: Ramachandran et al.

Group Art: 1746

Serial No.: 09/204,706

Examiner: A. Olsen

Filing Date: December

December 3, 1998

Title: REMOVAL OF POST-RIE POLYMER)

ON Al/Cu METAL LINE

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TC 1700

AMENDMENT UNDER 37 C.F.R. §1.115

Honorable Commissioner of Patents and Trademarks Washington, D.C. 20231

Sir:

In reply to the Office Action mailed April 11, 2001, which rejected the claims in the above-identified patent application, applicants respectfully request reconsideration, based upon the amendments hereinafter set forth

IN THE CLAIMS:

13. (Amended) In a metal etch tool for removing post-RIE polymer rails formed on a Al/Cu metal line of semiconductor structure, the improvement comprising: an integrated metal etch tool comprising [a] separate chamber means for

forming a water-only plasma process to strip the photoresist layer of a semiconductor [or micro-electronic]
composite structure previously subjected to a RIE process; and
separate chamber means for

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